Date Created: 2/9/2004
Date Issued: 2/24/2004
PCN # 20040606

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

If you have any questions concerning this change, please contact:

Name: LEE, JEONGSOO
E-Mail: JEONGSOO.LEE@notes.fairchildsemi.com
Phone: 82-32-680-1744

PCN Originator
Name: LEE, JEONGSOO
E-mail: JEONGSOO.LEE@notes.fairchildsemi.com
Phone: 82-32-680-1744

REL Engineer
Name: KIM, YONG_HYUN
E-mail: YONG_HYUN.KIM@notes.fairchildsemi.com
Phone:

PCN Type: Die Shrink

Effectivity
Expected 1st Device Shipment Date: 5/24/2004
Earliest Year/Work Week of Changed Product: 0422
(Note: Package marking may differ from this format)

Product ID (Description):
Some High Voltage Switch Mode Applications Transistors.

Description of Change:
This change will not affect any electrical characteristics.
This change will enlarge the production capacity to meet customer's need.

□ Time table

Finished Goods Status				Remark
Current (~ Feb.24.04).	Via (Feb.25.04 ~ May.24.04)	Via (May.25.04 ~ Nov.24.04)	Future (Nov. 25.04 ~)	
S	**N**	**L**	**K**	"S" code ➔ Fully Released for sale "N" code ➔ Not Recommended for new design "L" code ➔ Lifetime buys being accepted " K" code ➔ No new orders, Shipping only

Fairchild Semiconductor will change 'Finished Goods Status' code from "S" to "K" via "N", "L".

Effect of Change:
This change will not affect any electrical characteristics.
This change will enlarge the production capacity to meet customer's need.

Qualification:
The qualification plan is intended to meet all our criteria for qualifying new version dies and the overall quality and reliability of our products.

Qual/REL Plan Numbers

Additional Qualification Data

□ Reliability Test Item.

Test #	Test Description	Conditions	Duration
1	High Temperature Reverse Bias (HTRB)	150□, Vr=80% rated BV	168hrs
			500hrs
			1,000hrs
2	Temperature Humidity Bias Test (THBT)	85□, 85%RH Vr=10V	48hrs
			500hrs
			1,000hrs
3	Temperature Cycle (TMCL)	-65□ to 150□, 15min dwell (air to air)	200cyc
			500cyc
4	Autoclave (ACLV)	121□, 15psil, 100%RH	48hrs
			96hrs

□ Results of Reliability Test.

PRODUCT	Description	Test Items & Results				
		HTRB (Hrs)	THBT (Hrs)	Precon (Hrs)	TMCL (Cycles)	ACLV (Hrs)
FJP3305	TO-220 NPN 400V/4A	0/77(168) 0/77(500) **0/77(1000)**	0/77(168) 0/77(500) **0/77(1000)**	-	0/77(200) **0/77(500)**	0/77(48) **0/77(96)**
FJPF3305	TO-220F NPN	0/77(168) 0/77(500)	0/77(168) 0/77(500)	-	0/77(200) **0/77(500)**	0/77(48) **0/77(96)**

	400V/4A	**0/77(1000)**	**0/77(1000)**			
FJP5027	TO-220 NPN 800V/3A	0/77(168) 0/77(500) **0/77(1000)**	0/77(168) 0/77(500) **0/77(1000)**	-	0/77(200) **0/77(500)**	0/77(48) **0/77(96)**
FJPF5027	TO-220F NPN 800V/3A	0/77(168) 0/77(500) **0/77(1000)**	0/77(168) 0/77(500) **0/77(1000)**	-	0/77(200) **0/77(500)**	0/77(48) **0/77(96)**
Results of Reliability Test are All Pass!						

Affected FSIDs

KSC5027FO
KSC5027FOTU
KSC5027FR
KSC5027FRTU
KSC5027FRYDTU
KSC5027O
KSC5027ON
KSC5027OTU
KSC5027R
KSC5027RHTU
KSC5027RTU
KSE13005A
KSE13005ATU
KSE13005F
KSE13005FH1
KSE13005FH1TU
KSE13005FH2
KSE13005FH2TU
KSE13005FTU
KSE13005H1A
KSE13005H1ATU
KSE13005H2A
KSE13005H2ATU